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| <b>INFORMATION DISCLOSURE<br/>         STATEMENT BY APPLICANT<br/>         PTO FORM 1449</b> | Atty. Docket No.<br>10191/2287         |                         | Serial No.<br>To Be Assigned |
|  | Applicant(s)<br>Michael LINDNER et al. |                         |                              |
|  | Filing Date<br>Herewith                | Group<br>To Be Assigned |                              |

U. S. PATENT DOCUMENTS

| EXAMINER'S INITIALS | PATENT NUMBER | PATENT DATE       | NAME                | CLASS | SUBCLASS | FILING DATE |
|---------------------|---------------|-------------------|---------------------|-------|----------|-------------|
| SAT                 | 5,933,237*    | August 3, 1999    | Drabarek            |       |          |             |
| SAT                 | 5,493,398*    | February 20, 1996 | Pfister             |       |          |             |
| SAT                 | 5,155,363*    | October 13, 1992  | Steinbichler et al. |       |          |             |
| SAT                 | 3,849,003*    | November 19, 1974 | Velzel              |       |          |             |

\*Copy of reference is not enclosed because reference is cited in Search Report (copy of reference provided by International Searching Authority, and relevance noted in Search Report, copy of which is enclosed herewith).

FOREIGN PATENT DOCUMENTS

| EXAMINER'S INITIALS | DOCUMENT NUMBER | DATE               | COUNTRY | CLASS | SUB-CLASS | TRANSLATION |    |
|---------------------|-----------------|--------------------|---------|-------|-----------|-------------|----|
|                     |                 |                    |         |       |           | YES         | NO |
| SAT                 | 197 21 842***   | December 3, 1998   | DE      |       |           |             |    |
|                     | 41 08 944***    | September 24, 1992 | DE      |       |           |             |    |
|                     | WO 92 19930*    | November 12, 1992  | PCT     |       |           |             |    |
|                     | 03 120436*      | May 22, 1991       | JP      |       |           |             |    |
|                     | 196 25 830*     | January 2, 1998    | DE      |       |           |             |    |
| SAT                 | 197 21 843**    | February 11, 1999  | DE      |       |           |             |    |

\*Copy of reference is not enclosed because reference is cited in Search Report (copy of reference provided by International Searching Authority, and relevance noted in Search Report, copy of which is enclosed herewith).

\*\* Described in Specification.

OTHER DOCUMENTS

| EXAMINER'S INITIALS | AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.  |
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| SAT                 | Patent Abstracts of Japan, vol. 015, no. 327 (P-1240), (August 20, 1991).*  |
| SAT                 | P. de Groot, L. Deck, "Surface Profiling by Analysis of White-Light Interferograms in the Spatial Frequency Domain" J. Mod. Opt., Vol. 42, No. 2, 389-401, (1995)."     |
| SAT                 | No. T. Maack, G. Notni, W. Schreiber, W.-D. Prenzel, "Endoscopic 3-D Shape Measuring System", Jahrbuch fur Optik und Feinmechanik, Ed. W.-D. Prenzel, 231-240, (1998)." |

\*Copy of reference is not enclosed because reference is cited in Search Report (copy of reference provided by International Searching Authority, and relevance noted in Search Report, copy of which is enclosed herewith).

\*\* Described in Specification.

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| EXAMINER<br><i>S.A. Turner</i>  | DATE CONSIDERED<br>6-25-04 |
| EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. |                            |